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## AI Test

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Deadline for manuscript  
submissions:

**closed (31 January 2024)**

## Message from the Guest Editors

Dear Colleagues,

Topics of interest include, but are not limited to:

- Quality models, quality attributes and metrics for AI applications, such as robustness, fairness, reliability and performance.
- Testing methods, techniques and tools for various aspects and activities of testing and quality assurance, especially for test case generation, test oracle, and test adequacy measurements.
- Test automation environment and platforms for AI applications and by employing AI techniques.
- Domain specific testing techniques and methods for various special domains of AI applications, such as AI applications in natural language processing such as ChatGPT, image recognitions, time series and Internet of Things data analysis, medical and healthcare, robotics, software code generation/debugging/design, etc.
- Testing and quality assurance for various specific AI techniques, such as clusters and classifiers, regression machine learning models, deep neural networks, big models, recurrent neural networks, etc.



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## Editor-in-Chief

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## Message from the Editor-in-Chief

*Electronics* is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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